

## **Notice of References Cited**

Application/Control No. 09/788,388	Reexamina	Applicant(s)/Patent Under Reexamination OKADA ET AL.		
Examiner	Art Unit			
Chongshan Chen	2172	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,473,753	10-2002	Katariya et al.	707/4
	В	US-			
	С	US-			
	D	US-		,	
	Ε,	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-		·	
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11-242545	09-1999	Japan	Norihiko	G06F 3/00
	0	JP 05-307569 🗸	11-1993	Japan	Hideaki et al.	G06F 15/40
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	

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